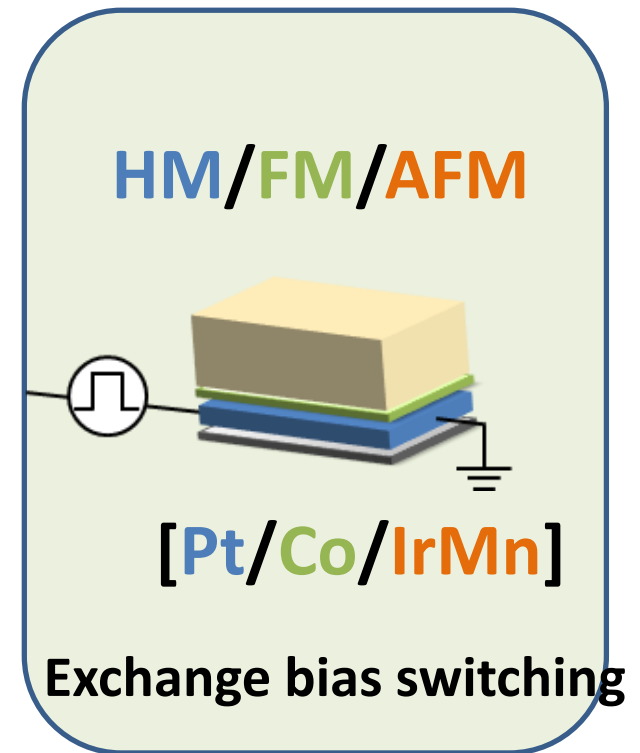
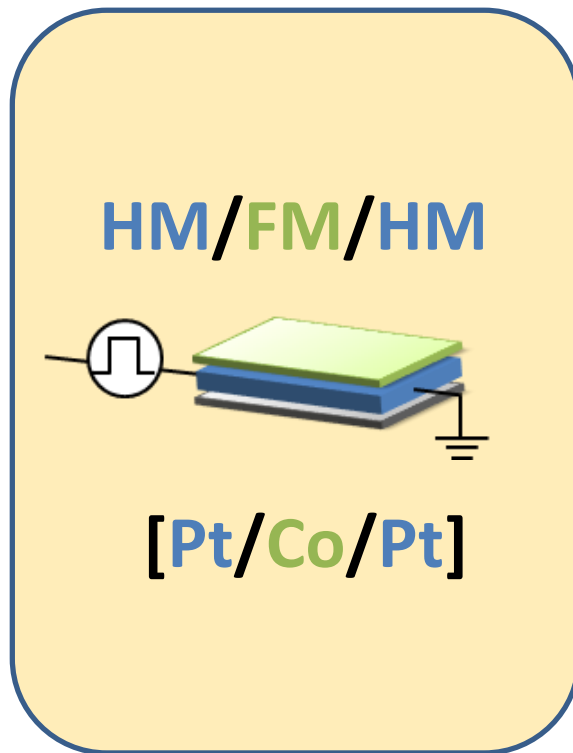


# Manipulating Exchange Bias by Spin-Orbit Torque

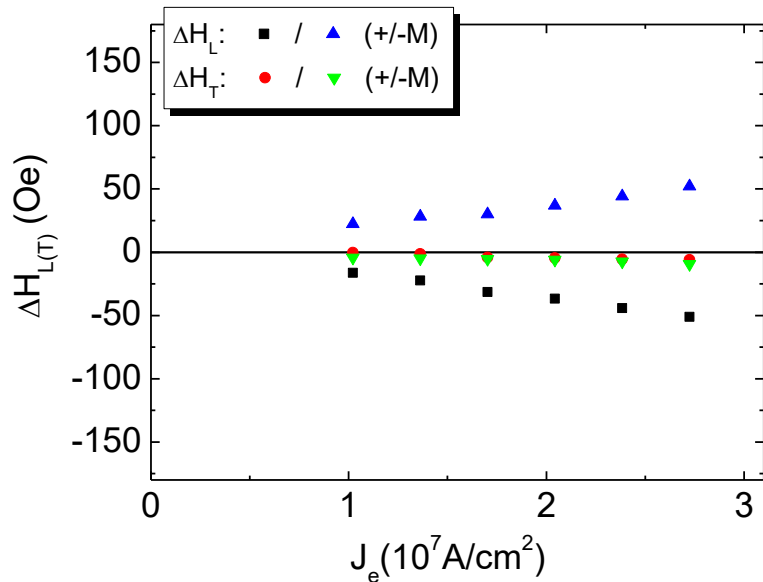
*Chih-Huang Lai*

*Materials Science and Engineering,  
National Tsing Hua University, Taiwan*

# Outline

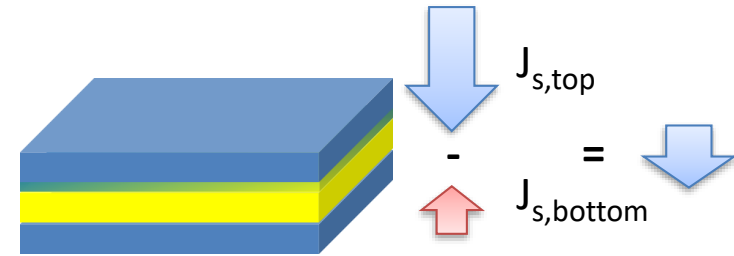


# Effective fields induced by Spin-orbit torque in Pt/Co/Pt

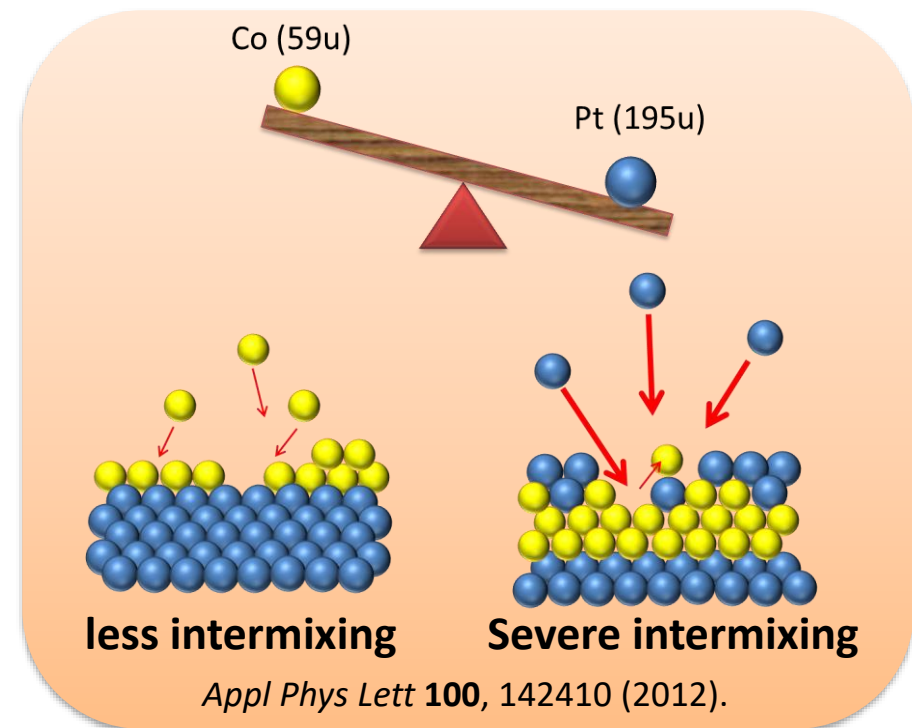


Pt (2 nm)/ Co (0.9 nm)/ Pt (2 nm)/

➤ Spin Hall effect dominated ( $\Delta H_L \gg \Delta H_T$ )

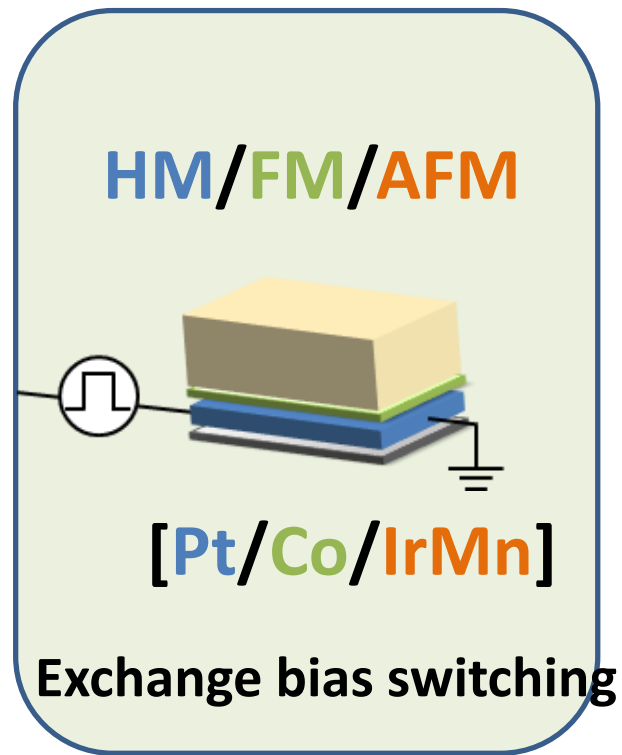


Different interface structure



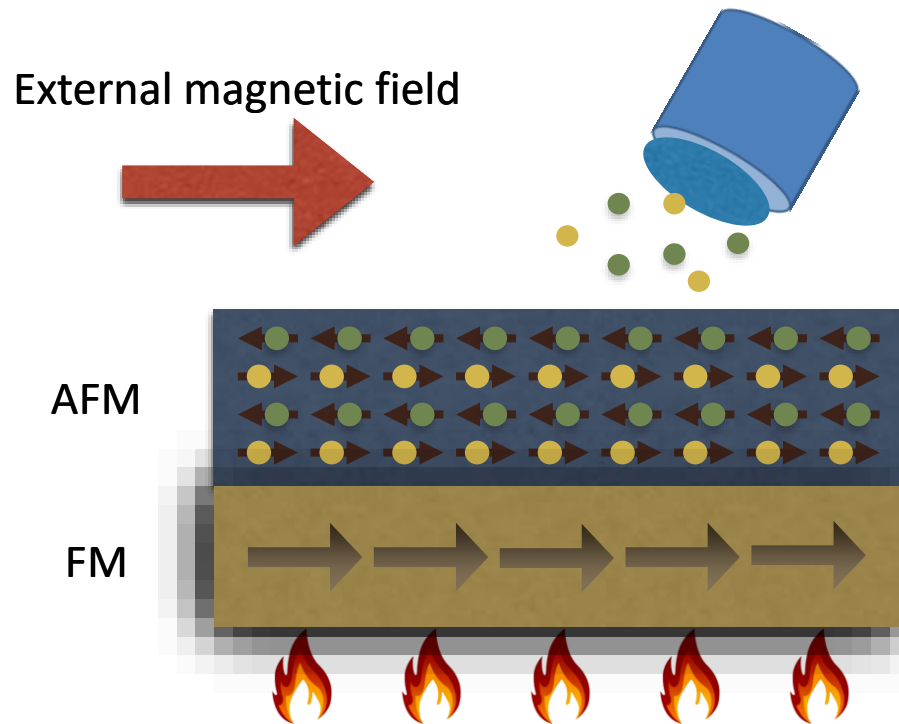
Huang and Lai, *APL*, **107**, 232407(2015)

# SOT in Pt/Co/IrMn



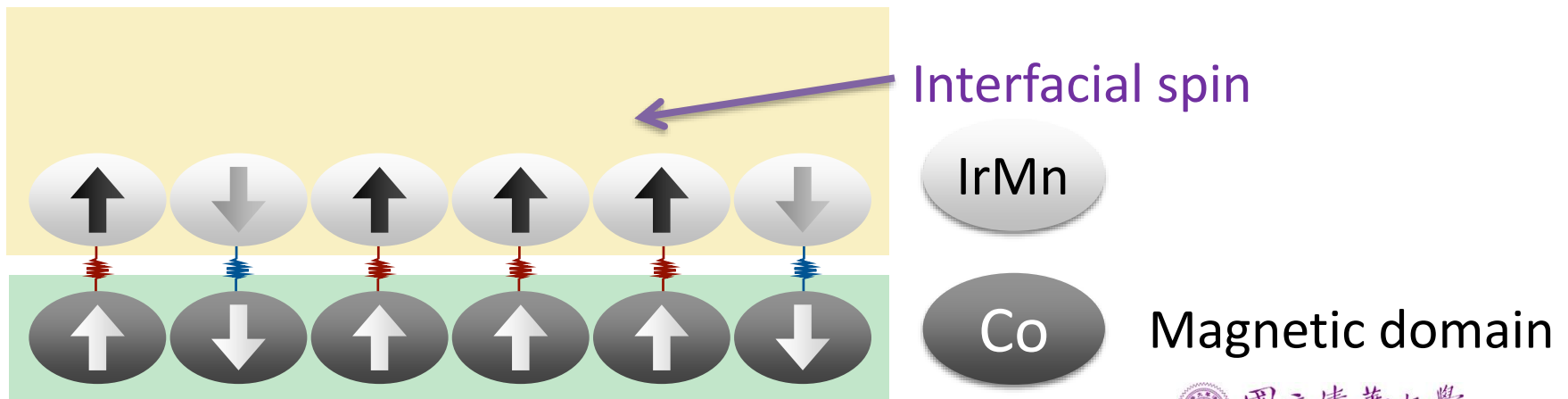
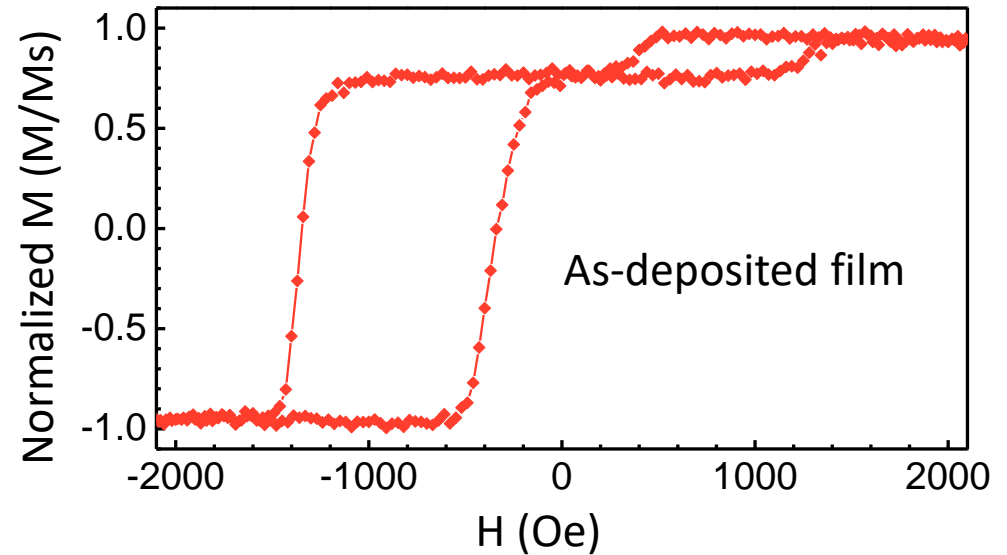
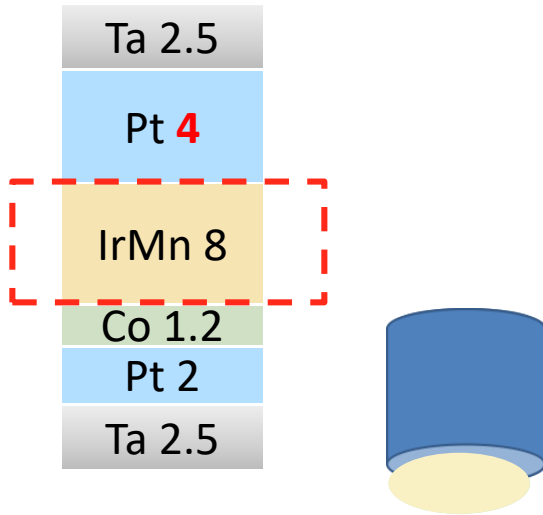
# Exchange bias of FM/AFM

- Align the interfacial spins of AFM with FM magnetization

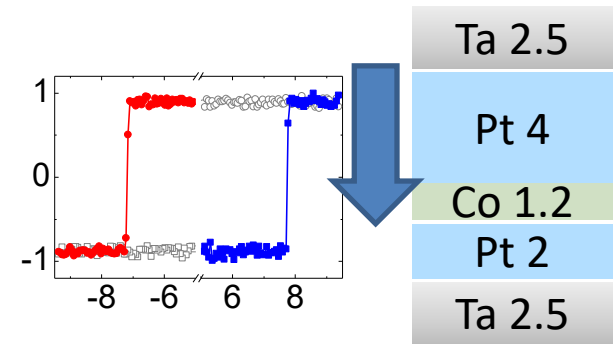
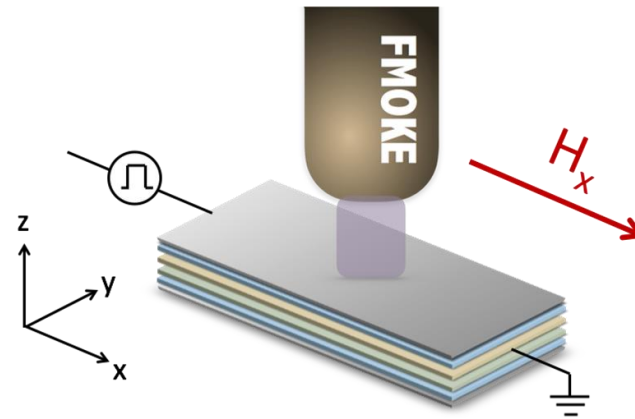


1. Deposition with external magnetic field.
2. Field-cooling

# Magnetic property of as-deposited film



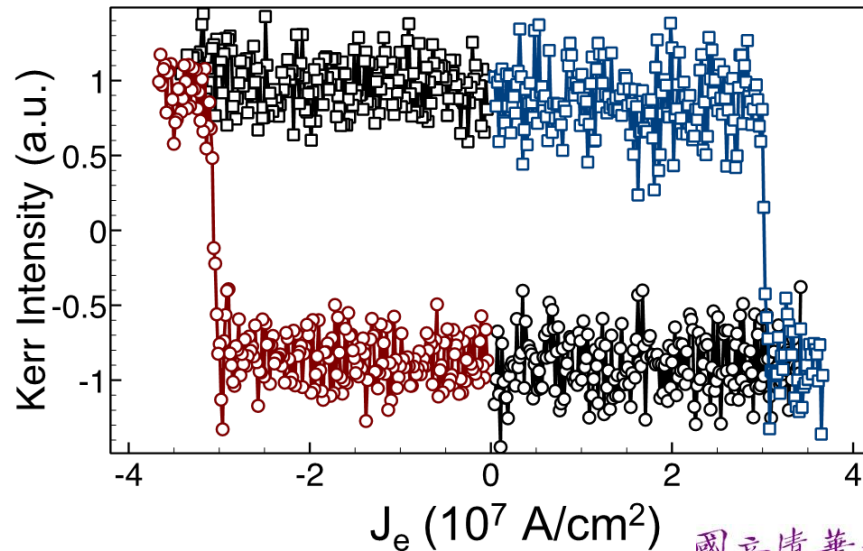
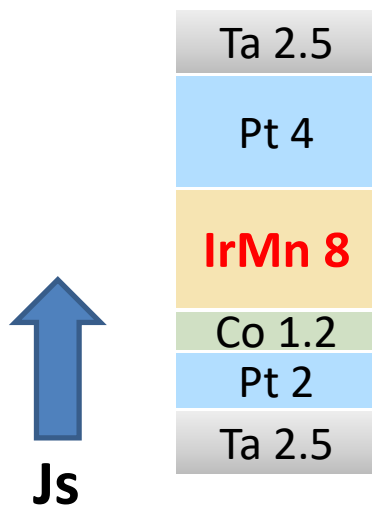
# SOT switching curve



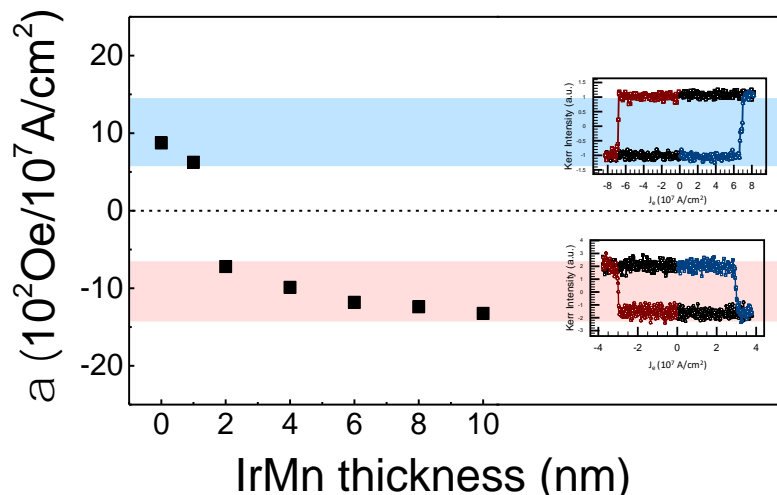
Device:  $5 \times 10 \mu\text{m}^2$

$H_x = 300 \text{ Oe}$

$I_{\text{pulse}} = 20 \text{ ns} - 10 \text{ us}$



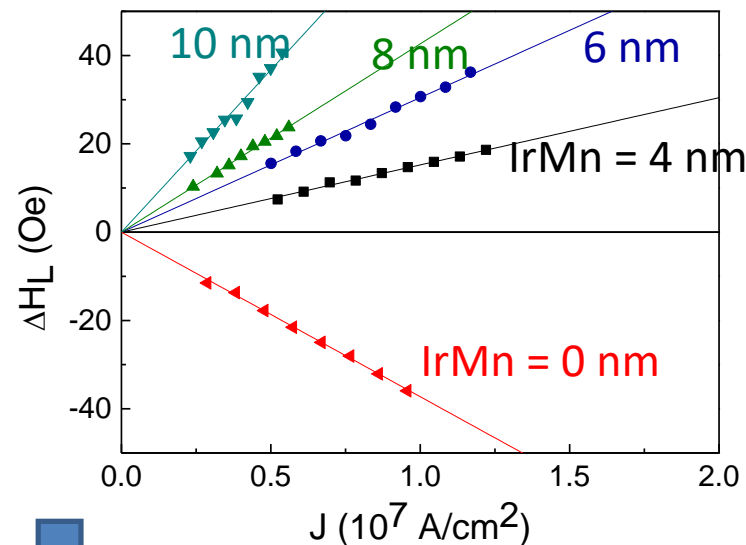
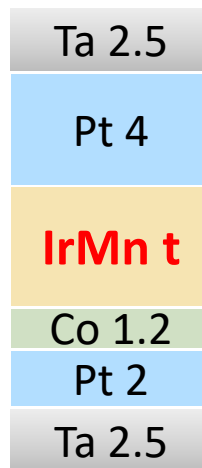
# Dominant spin current source



**SOT efficiency  $\alpha = H_K / J_c$**

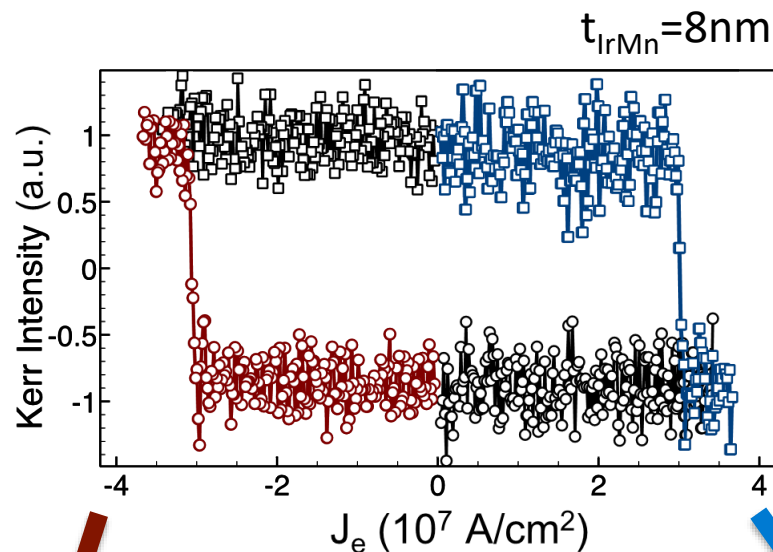
$H_K$  : anisotropy field

$J_c$  : threshold current density

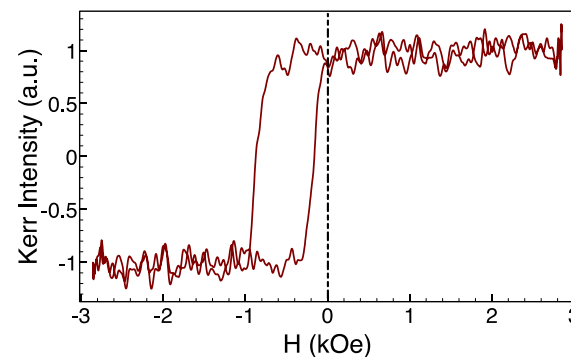




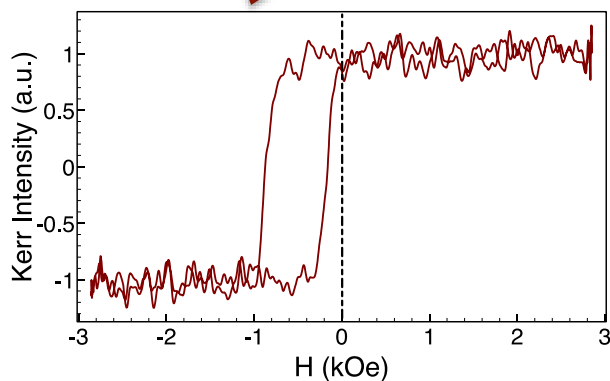
# Current-pulse-induced EB switching



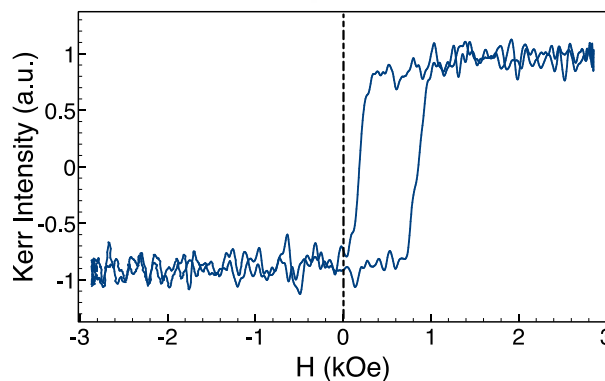
Initial EB



After -I  
SOT switching



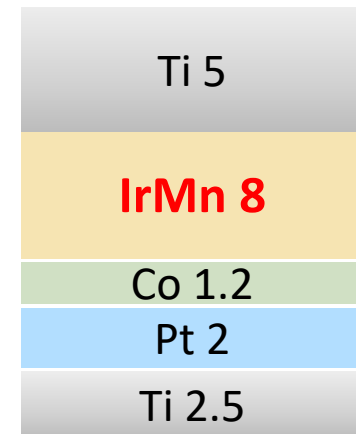
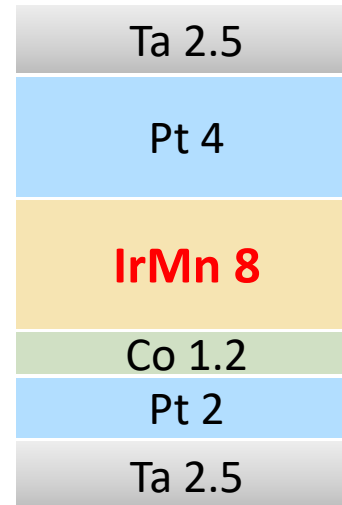
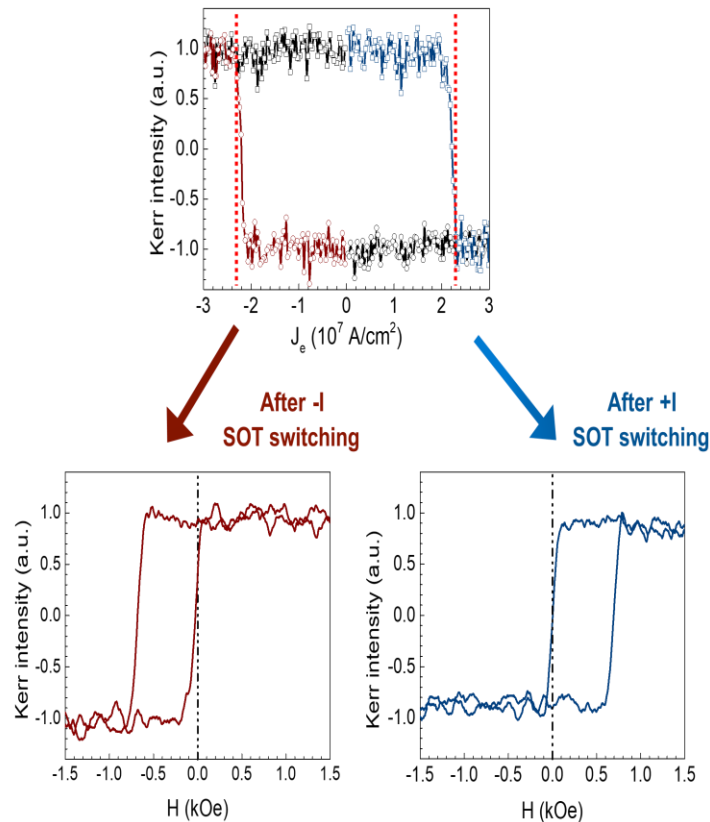
After +I  
SOT switching



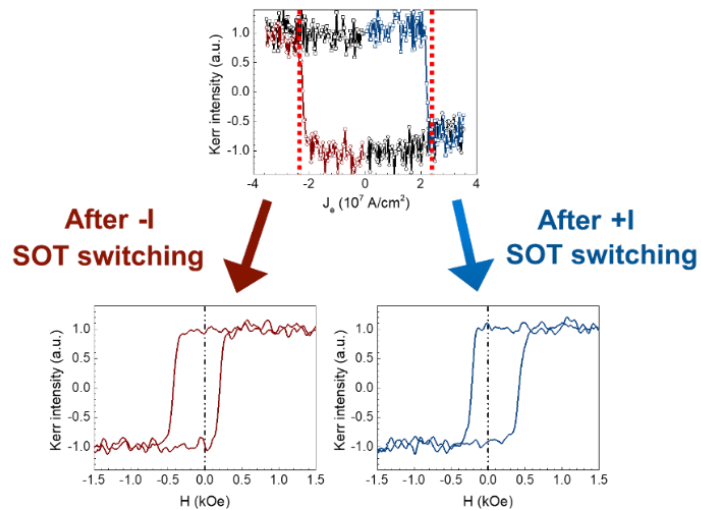
Lin and Lai, *Nature Materials*, **18**, 335 (2019)



# Dominant spin current source- bottom Pt



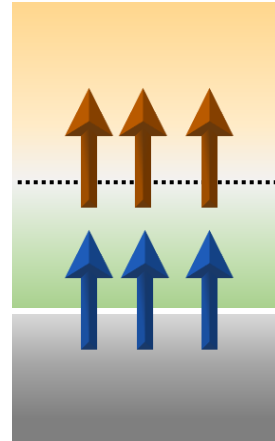
# Joule heating effect?



FeMn

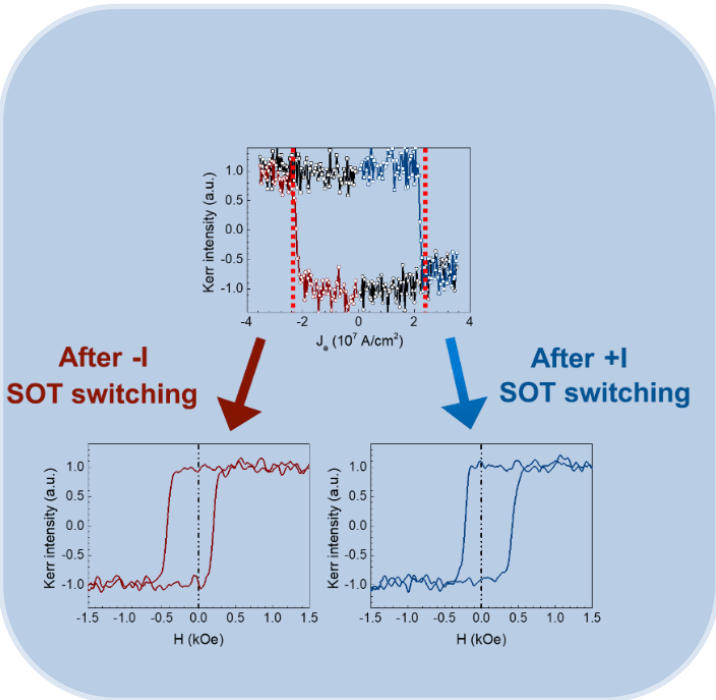
Co/Ni

Pt

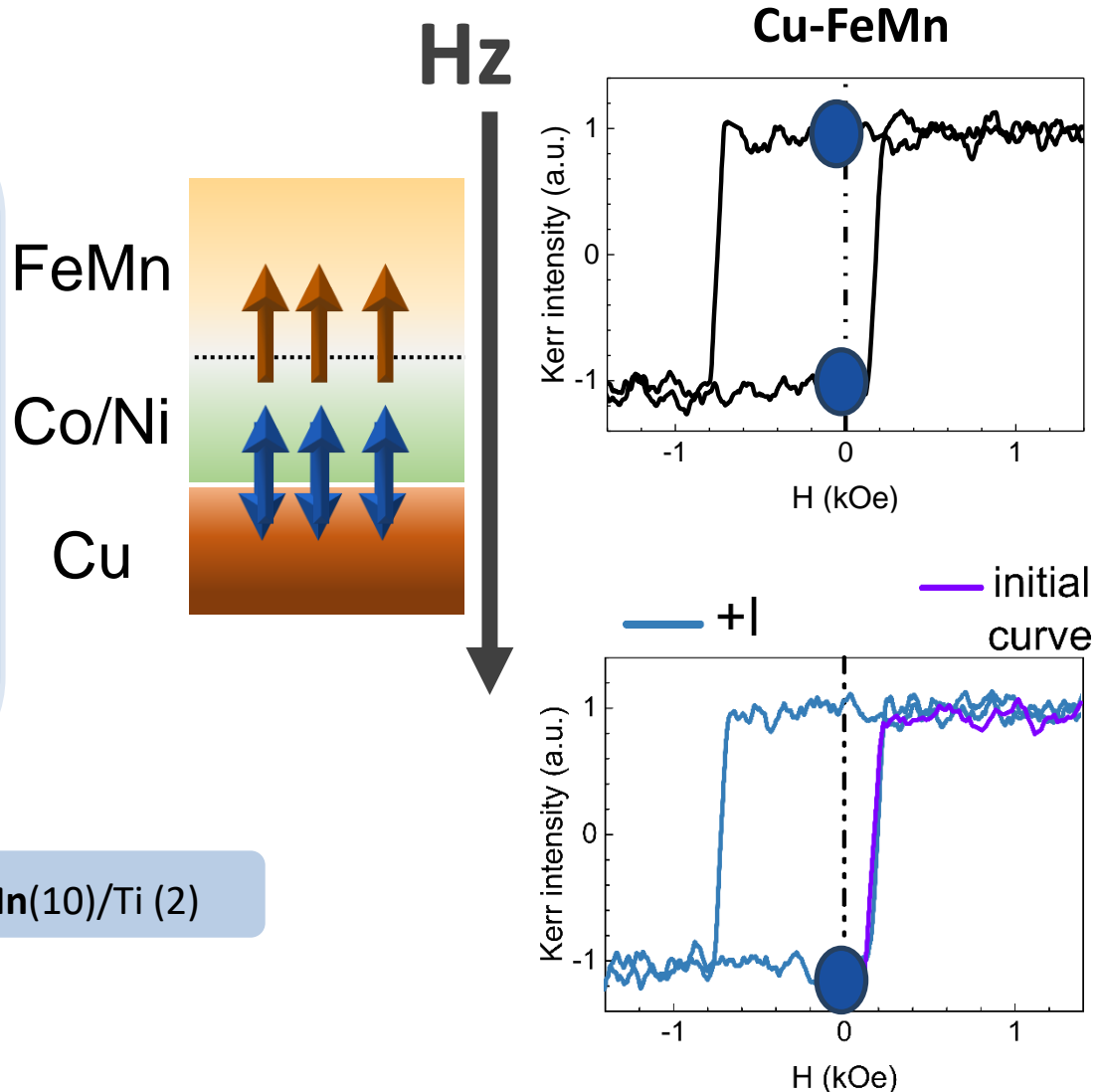


Sub./Ti(5)/Pt(5)/[Co(0.3)/Ni(0.6)]<sub>2</sub>/FeMn(10)/Ti (2)

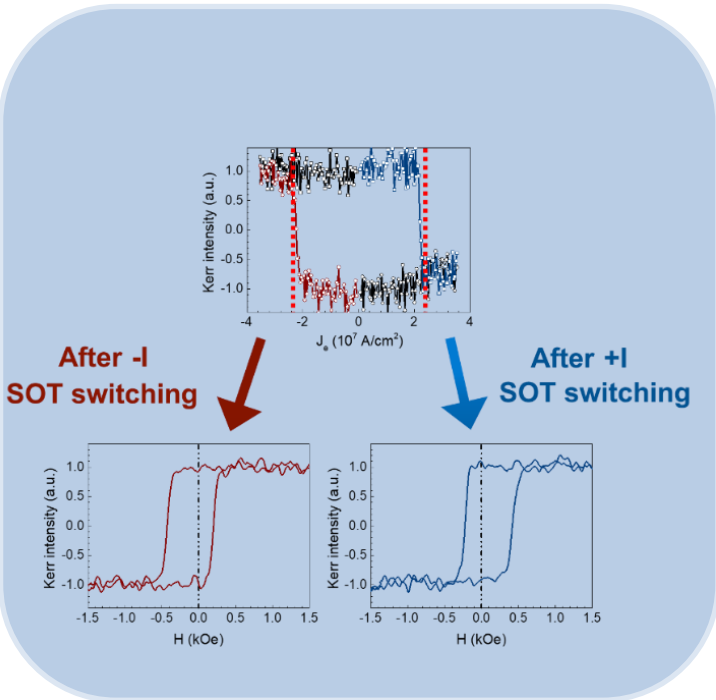
# Joule heating effect?



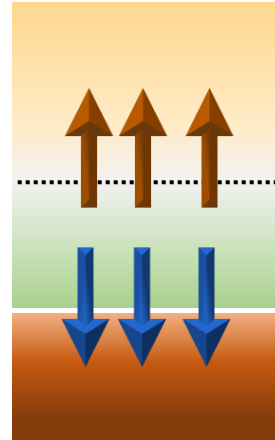
Sub./Ti(5)/Pt(5)/[Co 0.3)/Ni(0.6)]<sub>2</sub>/FeMn(10)/Ti (2)



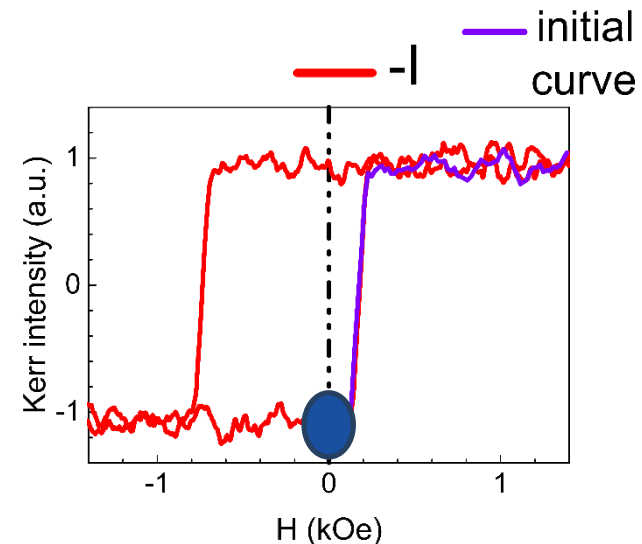
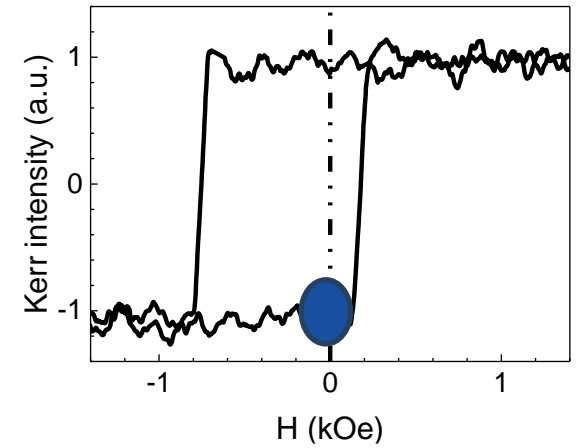
# Joule heating effect?



FeMn  
Co/Ni  
Cu

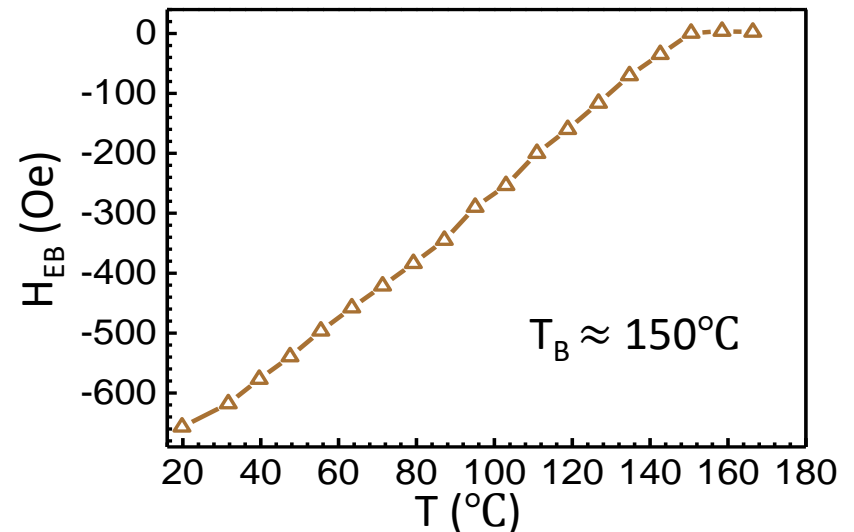
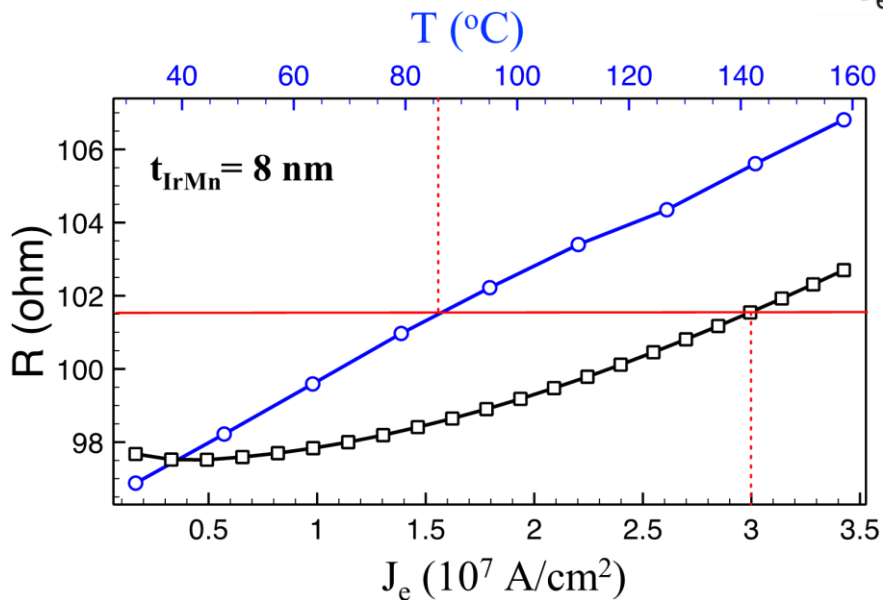
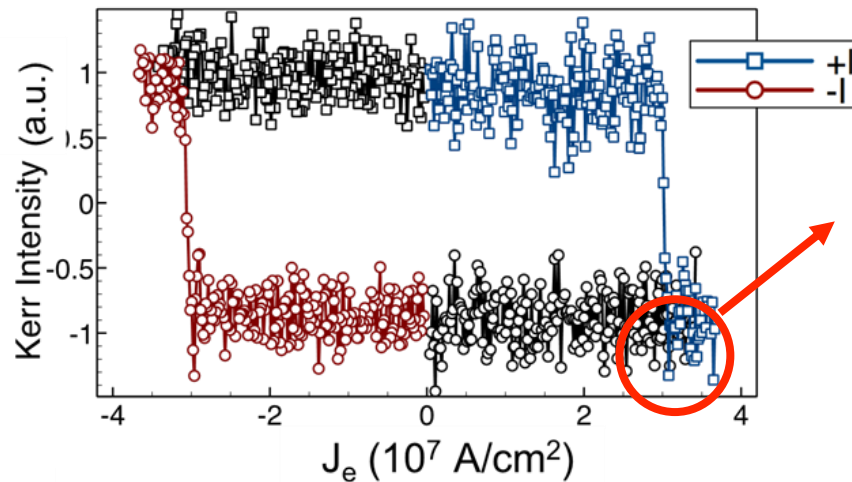


Cu-FeMn



Sub./Ti(5)/Pt(5)/[Co 0.3)/Ni(0.6)]<sub>2</sub>/FeMn(10)/Ti (2)

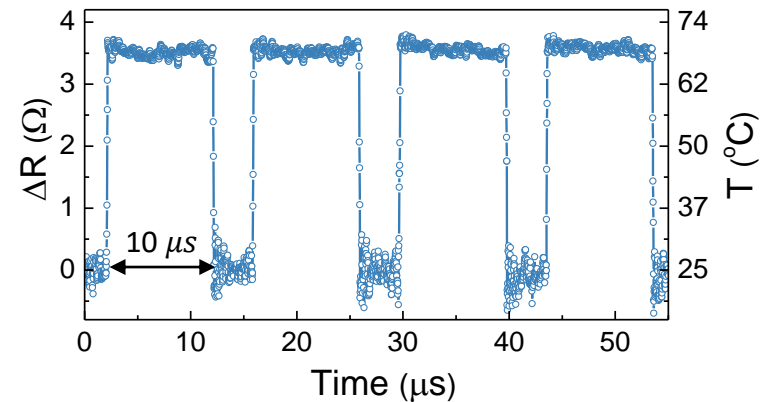
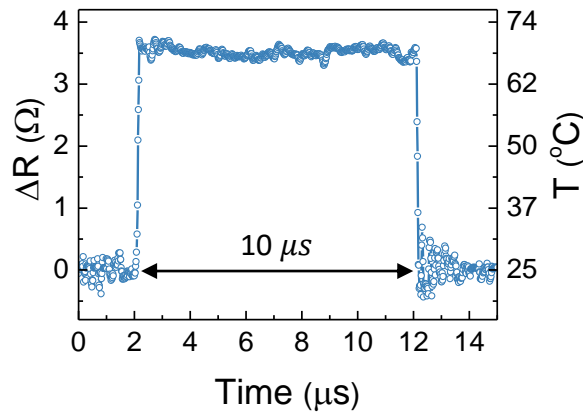
# Joule heating effect?



# Measurement of device temperature

Time-resolved resistance measurement (TRRM)

Pt 2/Co 1.2/IrMn 6 (nm)



$$\Delta R = R - R_0$$

$$T = T_0 + \gamma \Delta R = \mathbf{67.5 \pm 1.7^\circ C}$$

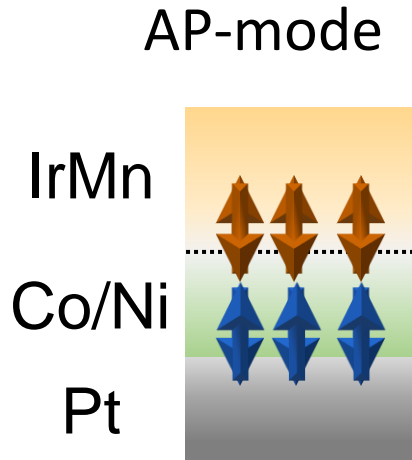
$$\gamma = 12.27 \text{ K}/\Omega, \text{ where } \gamma = dT/dR$$

Keithley 4200-SCS (Semiconductor Characterization System)  
with 4225-PMU Ultra Fast I-V Module

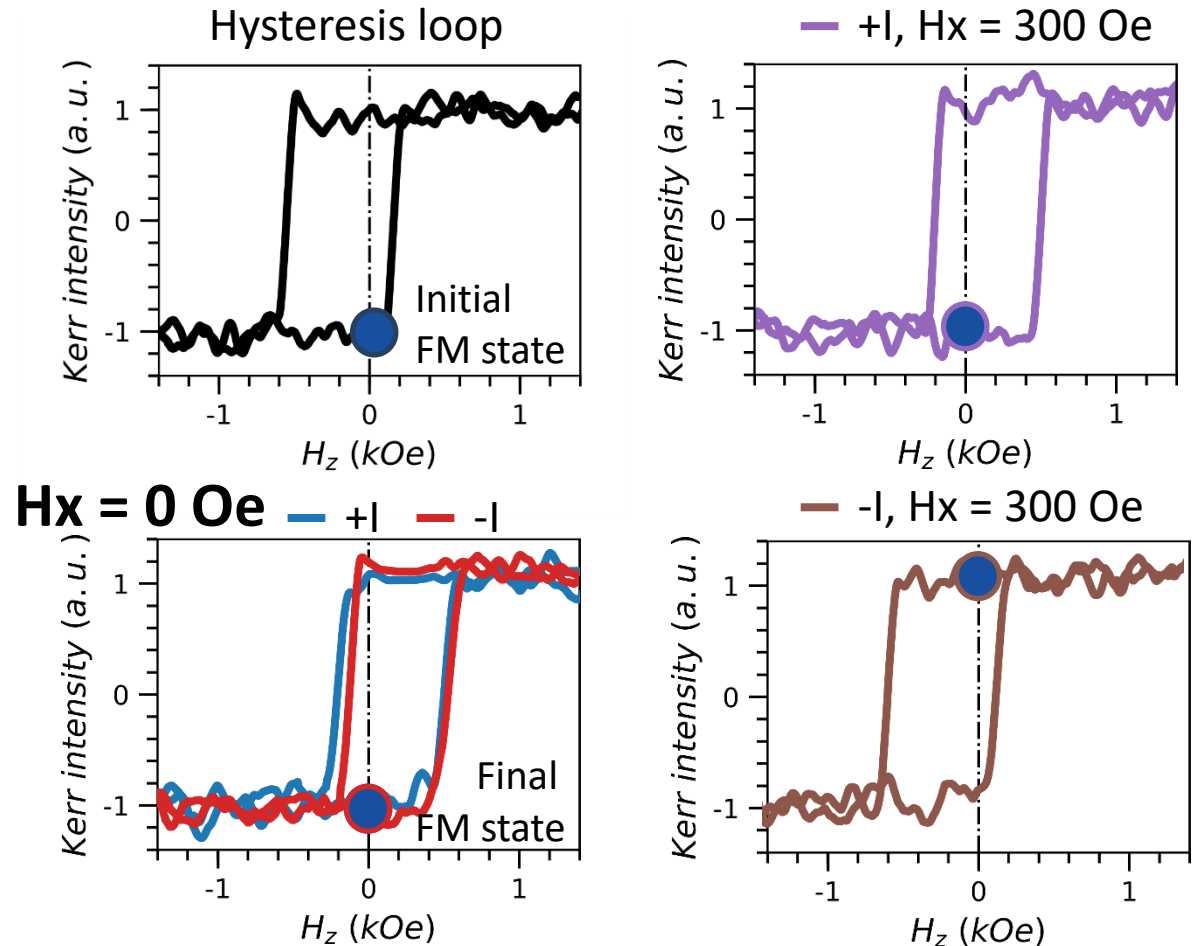
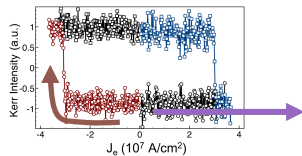
Pulse width = 10 us.

Current pulse amplitude = Jc

# Effects of $H_x$ on SOT switching of FM and EB



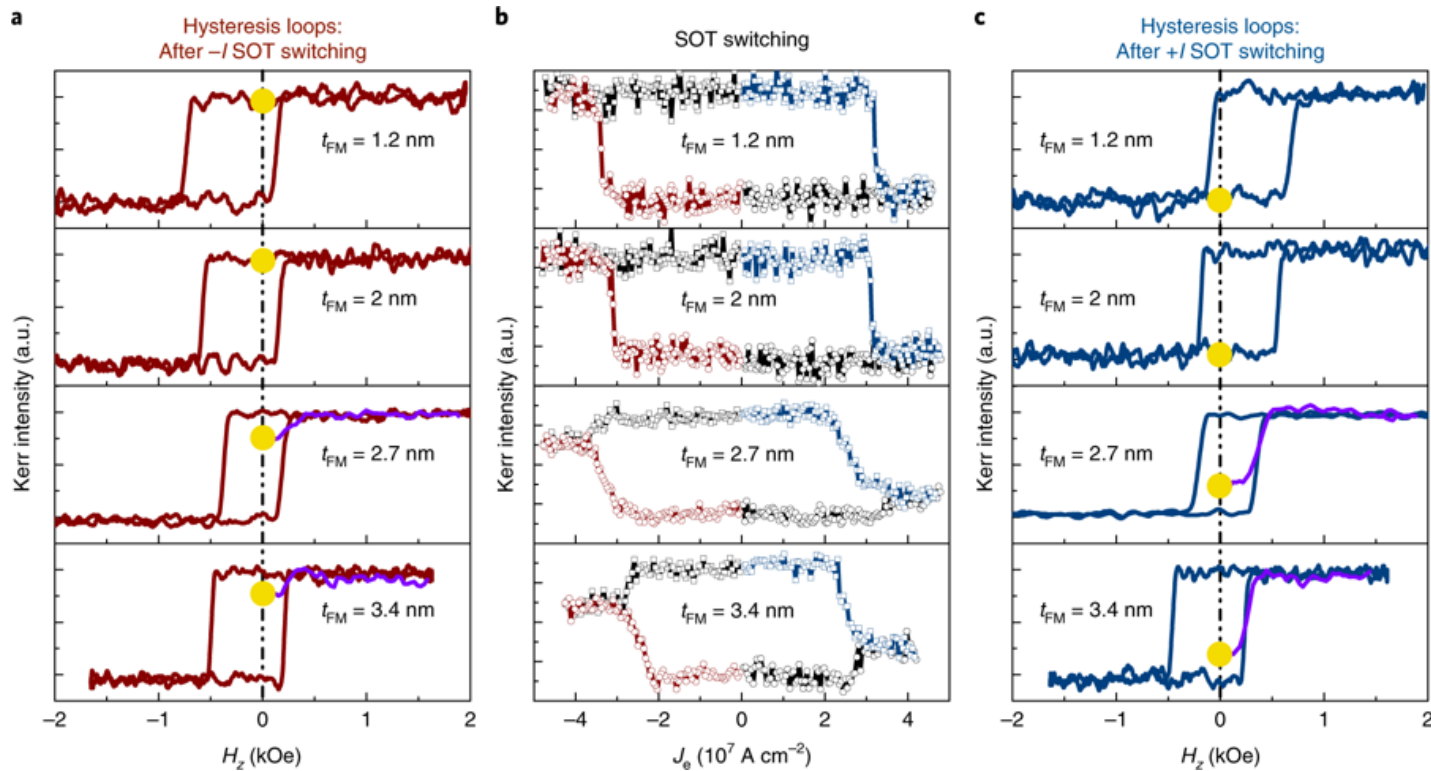
# SOT switching,  $H_x=300$  Oe



The reversal of interfacial spins depends on FM magnetization, regardless of  $H_x$ .  
The spin current provides disturbance for the interfacial spins to be aligned with FM.

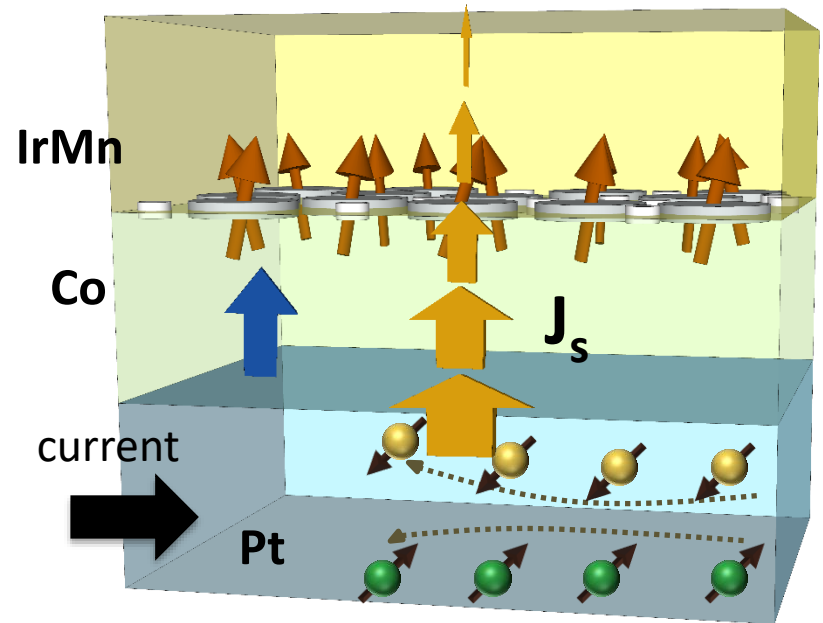
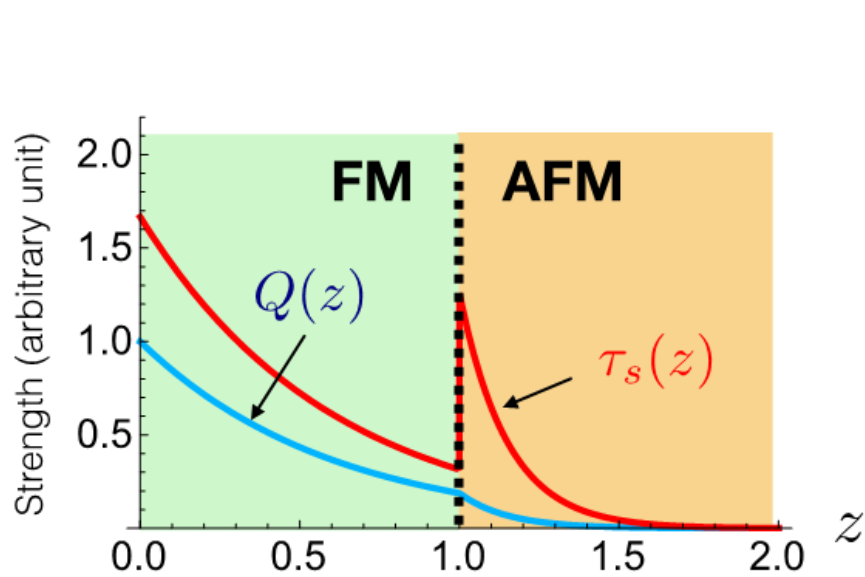


# How far can spin current go through the FM



For ferromagnetic layer thickness  $> 3.4$  nm, the EB is not switched

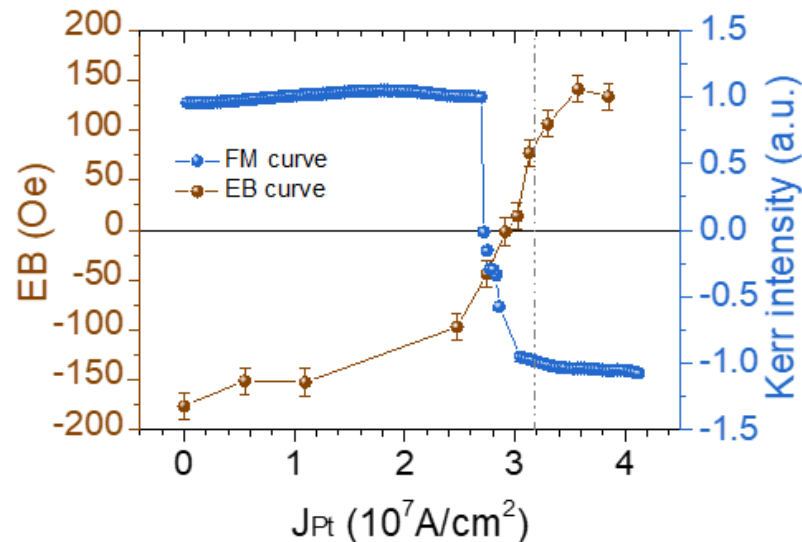
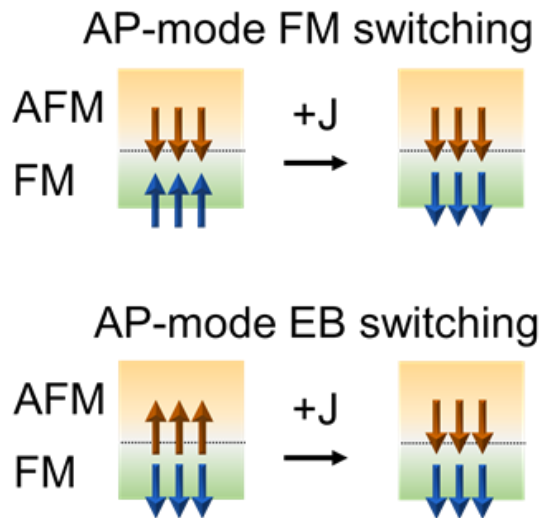
# Enhanced spin torque at FM/AFM interface



$$\frac{\partial \mathbf{m}}{\partial t} = -\gamma \mathbf{m} \times \mathbf{H}_{\text{eff}} + \alpha \hat{\mathbf{m}} \times \frac{\partial \mathbf{m}}{\partial t} - \frac{\delta \mathbf{m}}{\tau} - \nabla \cdot \mathbf{Q}$$

# SOT switching in AP-mode

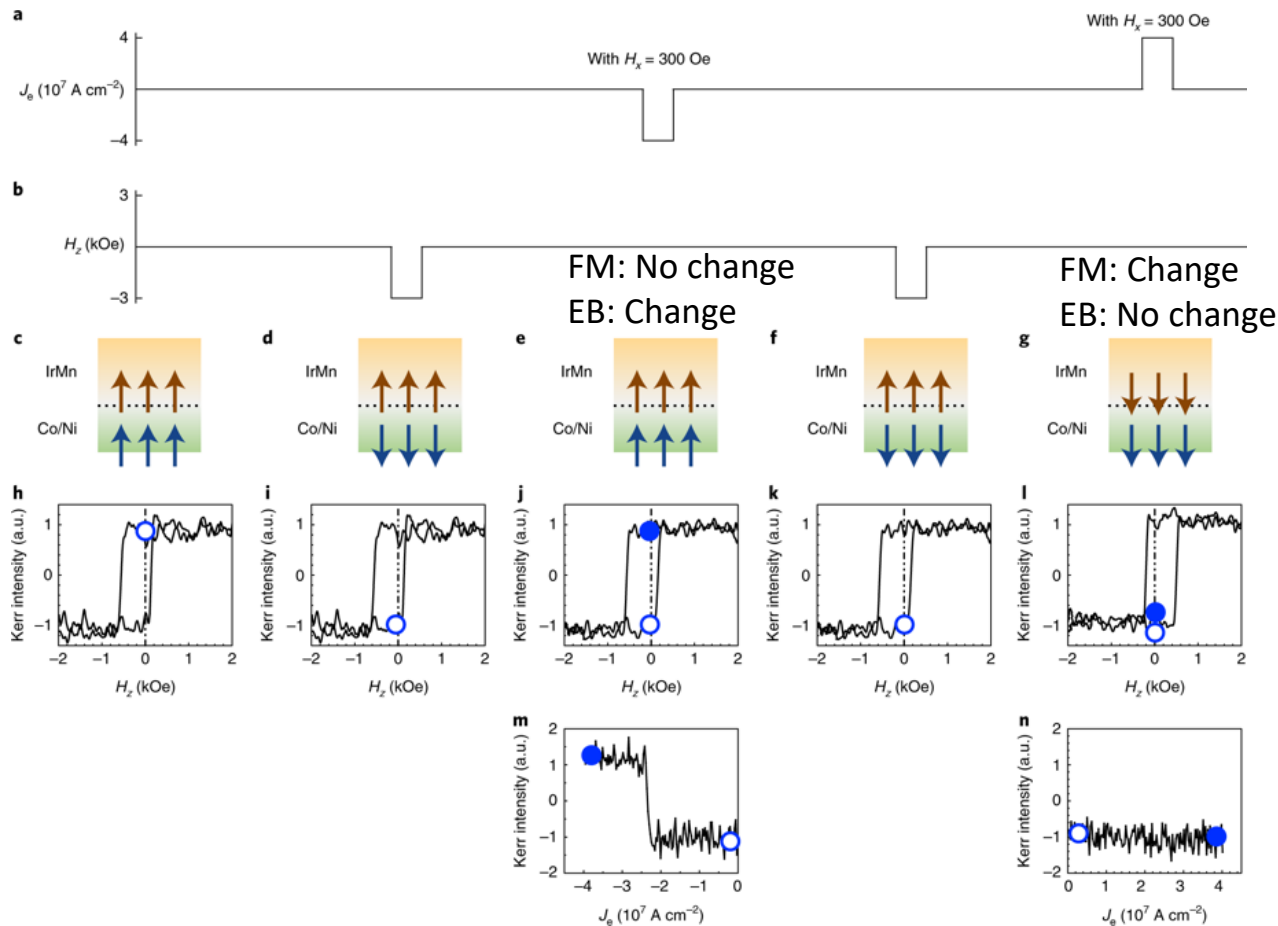
Pt(2)/ [Co(0.2)/Ni(0.8)]<sub>2</sub>/IrMn(8)



The closeness of FM and EB switching thresholds provides an indirect hint that SOT is the key for the switching mechanism.

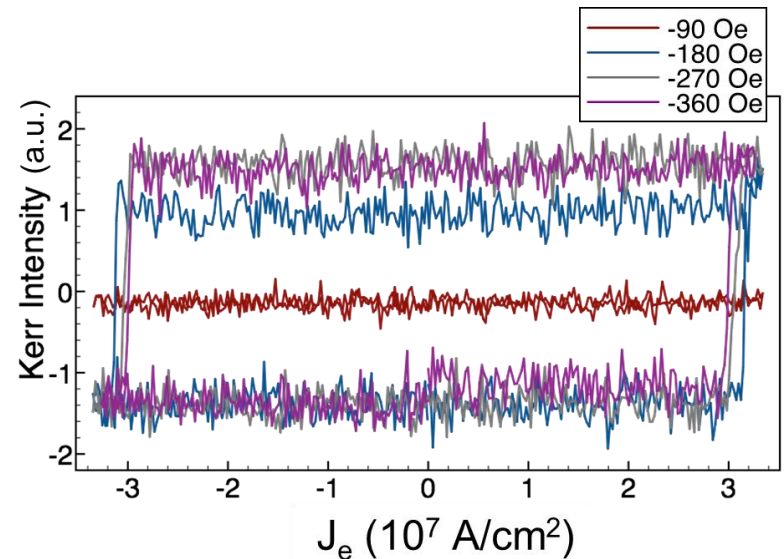
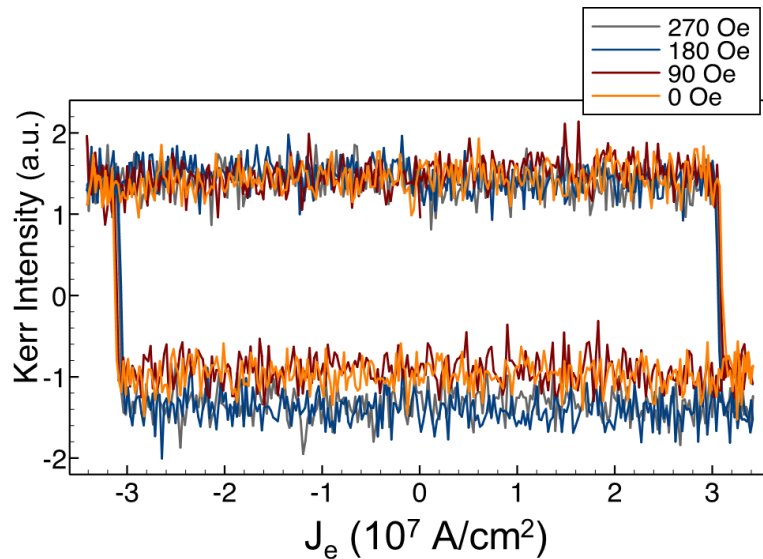
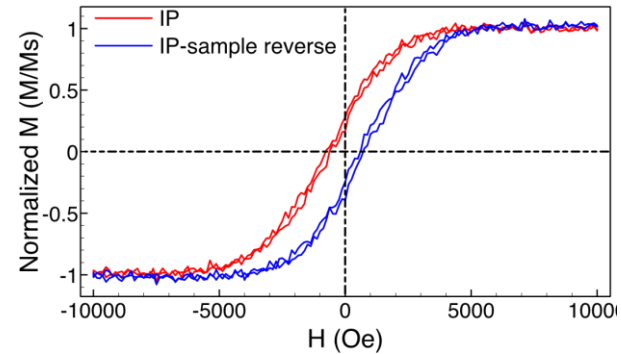
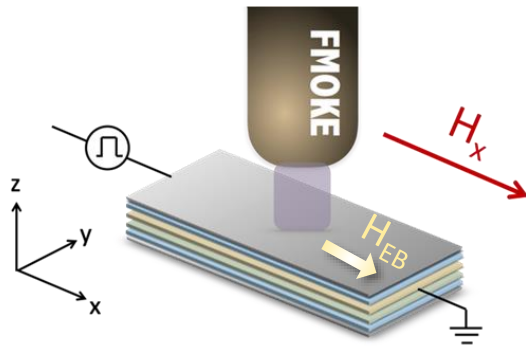
Flipping interfacial spins is accumulative and leads to smooth EB reversal, different from FM reversal.

# Independent SOT switching of ferromagnetic magnetization and exchange bias.



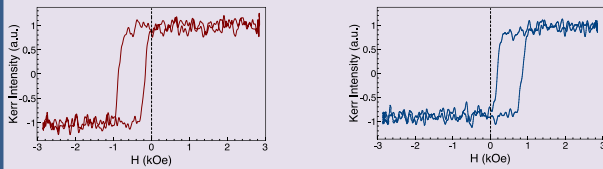
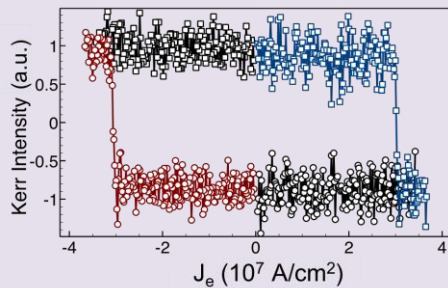
# Field-free switching

→ after In-plane annealing, the field free SOT switching can be accomplished



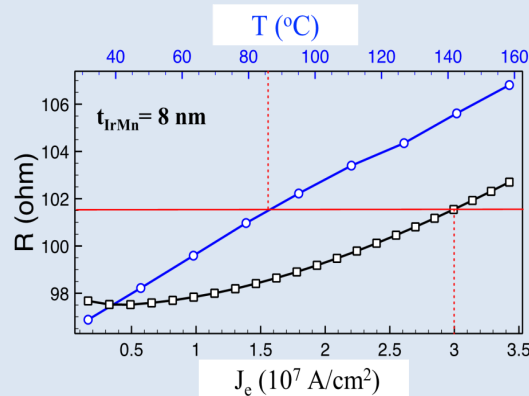
# Summary

## Current pulse-induced EB switching



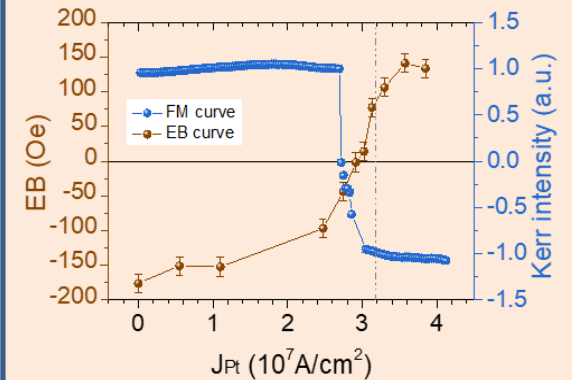
SOT does not only switch FM but interfacial AFM

## Joule heating is not a major factor



Temperature rise is much lower than  $T_B$

## SOT effects on FM and AFM are different



# Acknowledgement

- **Dr. Kuo-Feng Huang**
- **Dr. Ding-Shou Wang**
- **Mr. Po-Hung Lin**
- **Prof. Hsiu-Hau Lin( Physics, NTHU)**
- **Funding supported by Ministry of Science and Technology (MOST), Taiwan and Applied Materials Co.**

A 3D rendering of a microchip, tilted at an angle. The chip has a central orange and red area with yellow lines, surrounded by a blue and green border.

# Thank you for your attention!

Web page of our lab:  
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[chlai@mx.nthu.edu.tw](mailto:chlai@mx.nthu.edu.tw)

